

**Search Notes**

Application/Control No.

10/509,461

Examiner

Henok G. Heyi

Applicant(s)/Patent under  
Reexamination

VAN DEN OETELAAR ET AL.

Art Unit

2627

**SEARCHED**

Class	Subclass	Date	Examiner
369	275.1	11/6/2007	HH
369	94	11/6/2007	HH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST searched and consulted primary Tan Dinh.	11/6/2007	HH